

<b>Notice of References Cited</b>	Application/Control No. 10/598,181		Applicant(s)/Patent Under Reexamination VATANEN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,937,093	06-1990	Chino et al.	427/10
*	B	US-5,837,324	11-1998	Yapel et al.	427/402
*	C	US-6,248,406	06-2001	Kondo et al.	427/420
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05104062 A	04-1993	Japan	ARAI, TAKAO	B05D 07/00
	O	JP 06142590 A	05-1994	Japan	NAKAMURA et al.	B05C 05/02
	P	JP 2000343017 A	12-2000	Japan	OKADA et al.	B05C 05/02
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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